## Analysis of Manufacturing Process of a Semiconductor

**Technical Exercise - Phase 1** 



Lívia Parente

### Agenda

- Problem Context
- Objectives
- **♦** EDA
- Preprocessing Steps
- Model choice
- **♦** First Results

- Undersampling Strategy
- Hyperparameters Optimization
- Most important attributes
- **♦** Features selection
- Conclusion

#### Problem Context

Data collected from sensors of a manufacturing semiconductor process

Row count: 1567

Column count: 591

- Target variable values: Pass (1) or Fail (-1)
  - Binary classification problem

### Objectives

Build a Machine Learning model to predict the target variable.

2. Sort the attributes in terms of importance that produce a positive test.

3. Rebuild the model using the key attributes identified in the previous step and compare the performance with the initial model.

## EDA

**Exploratory Data Analysis** 

### EDA - Simple eye analysis

#### >>> data.head()

```
Time
                            0
                                                          587
                                                                 588
                                                                         589
                                                                              Pass/Fail
  2008-07-19 11:55:00
                      3030.93 2564.00 2187.7333
                                                         NaN
                                                                NaN
                                                                        NaN
                                                                                  -1
 2008-07-19 12:32:00
                      3095.78 2465.14 2230.4222
                                                        0.0201 0.0060
                                                                      208.2045
2 2008-07-19 13:17:00
                      2932.61 2559.94 2186.4111
                                                        0.0484 0.0148
                                                                      82.8602
3 2008-07-19 14:43:00
                      2988.72 2479.90 2199.0333
                                                        0.0149 0.0044
                                                                       73.8432
4 2008-07-19 15:22:00
                      3032.24 2502.87 2233.3667
                                                        0.0149 0.0044
                                                                       73.8432
```

```
>>> secom.shape (1567, 592)
```

## First conclusions

- First row has the name of features
- First column has time and data
- Last column has the labels
- Some NaN values
- Large Dataset 1567x592

### EDA - More immediate investigation

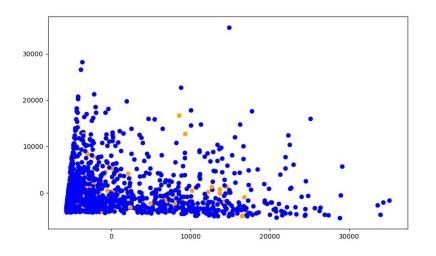
>>> 5	>>> secom.describe()						
	0	1	2		588	589	Pass/Fail
count	1561.000000	1560.000000	1553.000000		1566.000000	1566.000000	1567.000000
mear	3014.452896	2495.850231	2200.547318		0.005283	99.670066	-0.867262
std	73.621787	80.407705	29.513152		0.002867	93.891919	0.498010
min	2743.240000	2158.750000	2060.660000	•••	0.001000	0.000000	-1.000000
25%	2966.260000	2452.247500	2181.044400		0.003300	44.368600	-1.000000
50%	3011.490000	2499.405000	2201.066700		0.004600	71.900500	-1.000000
75%	3056.650000	2538.822500	2218.055500		0.006400	114.749700	-1.000000
max	3356.350000	2846.440000	2315.266700		0.028600	737.304800	1.000000

### Other conclusions

- A big number of NaN or null values
- Features with completely different magnitudes

## PCA for data visualization

Feature reduction from 591 to 2



→ Classes not easily separable

## Preprocessing

## First preprocessing steps

- Separate Data and labels
- Remove first column with dates
- Substitute Nan for mean values
- Eliminate possible erroneous values, e.g. 0.0

#### Result:

→ Number of features columns reduced from 590 to 478

## Other preprocessing steps

- Split the data by 20% to training test sets
- Standardize features to deal with different features magnitudes

## Model choice

#### Model choice

#### Must take into account:

- → Classification problem
- → Large Dataset

K-means and Naive Bayes do not perform well on large dataset.

#### It leaves us with:

- → Support Vector Machines: Computationally cheap, only handles binary classification
- → Decision Trees: Computationally cheap, can deal with irrelevant features, but tends to overfit
- → Random Forests: Can also deal with irrelevant features but has lower tendency to overfit

## Random Forests

Additionally gives us importance of variables

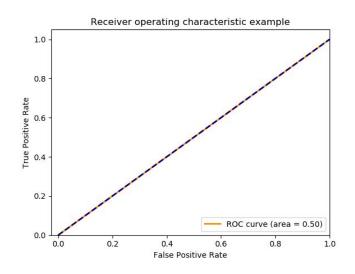
#### First results

By simply trying the standard parameters with the chosen model and preprocessing steps described

	Precision	Recall	F1-Score
-1	0.93	1.00	0.97
1	0.00	0.00	0.00

#### **Confusion Matrix**

TP = 0	FN = 21
FP = 0	TN = 293



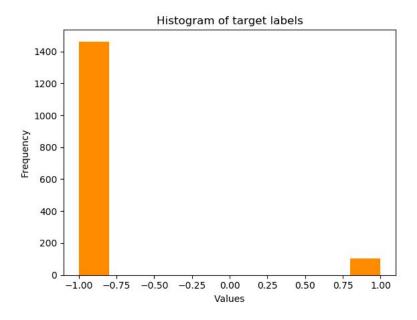
### Conclusion

- → Cannot predict positive values
- → Resulting label is always "Fail", regardless of the entries

#### Idea

→ Investigate problems on the Dataset

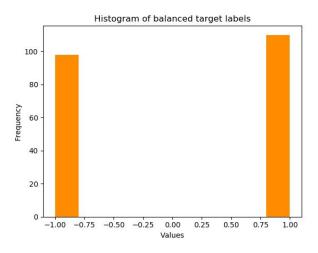
# Highly imbalanced classes



## Undersampling strategy

Since we have a large dataset

## Simply make an equal distribution of data according to the class labels



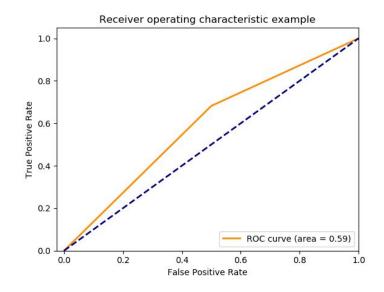
## Undersampling first try

Same number of "Pass" and "Fail" examples in the dataset

	Precision	Recall	F1-Score
-1	0.59	0.50	0.54
1	0.60	0.68	0.64

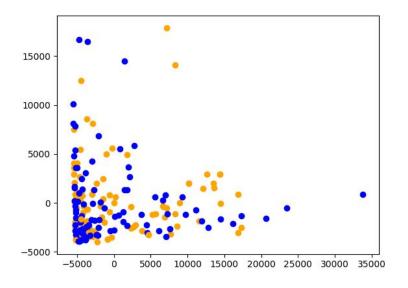
#### **Confusion Matrix**

TP = 15	FN = 7
FP = 10	TN = 10



## PCA for data visualization

→ After undersampling

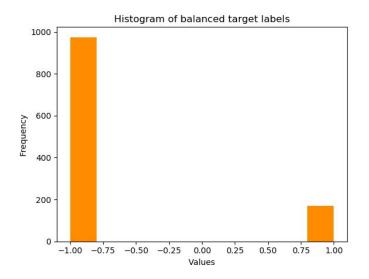


 Classes more balanced but still not easily separable

# Change the undersampling strategy

→ Too few data

## Manually exhausting optimization classes size



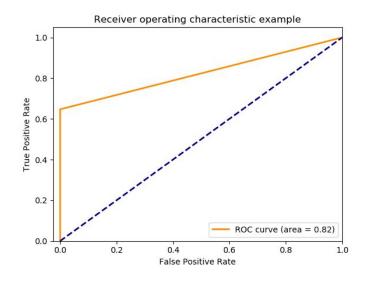
## Undersampling optimal sizes

"Fail" class 10x bigger than "Pass" class

	Precision	Recall	F1-Score
-1	0.94	1.00	0.97
1	1.00	0.65	0.79

#### **Confusion Matrix**

TP = 22	FN = 12
FP = 0	TN = 195



# Other undersampling strategy

Also tried "Tomek undersampling" technique, without any improvement

## Hyperparameters Optimization

### Hyperparameters to optimize

- Number of trees
- Function to measure the quality of split
- Maximum depth of the tree
- Minimum number of samples required to split a node
- Minimum number of samples at a leaf node
- The number of features to consider when looking for the best split

### Grid Search optimization strategy

- Exhaustive search
- 3-fold cross validation

## Hyperparameters chosen

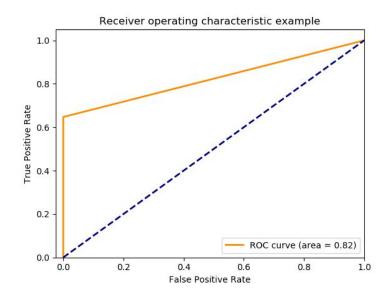
- Number of trees = 50
- Default values

	Precision	Recall	F1-Score
-1	0.94	1.00	0.97
1	1.00	0.65	0.79

→ Same results as before

#### **Confusion Matrix**

TP = 22	FN = 12
FP = 0	TN = 195



# Most important attributes

### Classifying attributes

The Random Forests model in the Scikit Learn framework provides an attribute that classifies features in terms of its importance to predict a positive value.

#### 10 most important attributes

feature	importance
59	0.016341
103	0.015929
341	0.011465
130	0.010547
129	0.009546
205	0.009080
477	0.008975
455	0.008767
519	0.008629
33	0.007735

#### → Remark:

Even the most important feature has very low importance, supporting the difficulty to predict the positive result.

## Features selection

### Features selection

Some feature selection strategies were tested:

- Selecting the best half of features
- Selecting the best 100 features
- Selecting the best 20 features
- Selecting features with importance bigger than 0.004, 0.002...
  - → But they all produced the same result as before, with no improvement

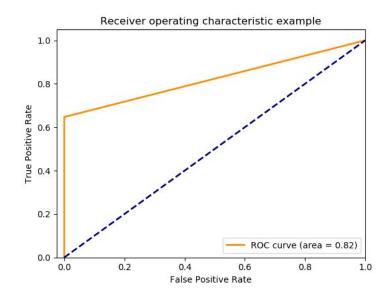
## Features selection result

#### → Same results as before

	Precision	Recall	F1-Score
-1	0.94	1.00	0.97
1	1.00	0.65	0.79

#### **Confusion Matrix**

TP = 22	FN = 12
FP = 0	TN = 195



### Conclusion

→ The models or the hyperparameters optimization did not provide us big changes

→ Even after applying some techniques the classes were not easily separable

- → The biggest problems in that case were the dataset itself
  - ♦ Unbalanced
  - ◆ Large

## Other ideas to try

- → Different resampling strategies
  - Oversampling after undersampling

→ Other feature selection strategie